

Search Notes

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Examiner

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Reexamination

EVEN ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
708	504, 650	3/19/2007	MAI

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	3/19/2007	MAI